


<b>Search Notes</b>  	<b>Application/Control No.</b>  10580052	<b>Applicant(s)/Patent Under Reexamination</b>  AKASHI ET AL.
	<b>Examiner</b>  Dawn L. Garrett	<b>Art Unit</b>  1794

SEARCHED			
Class	Subclass	Date	Examiner
428	690, 917 (see EAST history for all listed class/subclasses)	9-23-2008	DG
313	504, 506	9-23-2008	DG
257	40, E51.051	9-23-2008	DG
564	434	9-23-2008	DG

SEARCH NOTES		
Search Notes	Date	Examiner
STIC structure search by EIC 1700 (M. Huang) (see attached printouts)	9-23-2008 and 9-24-2008	DG
STN search of registry numbers (see attached)	9-23-2008	DG
EAST search (see printout); Databases: EPO, JPO, DERWENT, USPAT, USPGPUB	9-23-2008 and 9-24-2008	DG
Inventor Name Search	9-23-2008	DG

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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